

1.	Record Nr.	UNINA990001481330403321
	Titolo	Index herbariorum : a guide to the location and contents of the world's public herbaria / edited by J. Lanjouw
	Pubbl/distr/stampa	Utrecht : International Association of Plant taxonomy, 1957
	Descrizione fisica	120 p.
	Collana	Index Herbariorum ; 2 / 2
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	Collocazione	ERBARIO E-H
	Lingua di pubblicazione	Inglese
	Formato	Materiale a stampa
	Livello bibliografico	Monografia
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2.	Record Nr.	UNINA9910299951203321
	Autore	Champac Victor
	Titolo	Timing Performance of Nanometer Digital Circuits Under Process Variations / / by Victor Champac, Jose Garcia Gervacio
	Pubbl/distr/stampa	Cham : , : Springer International Publishing : , : Imprint : Springer, , 2018
	ISBN	3-319-75465-3
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	Descrizione fisica	1 online resource (195 pages)
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Nota di contenuto

Introduction -- Mathematical Fundamentals -- Process Variations -- Gate delay under process variations -- Path Delay Under Process Variations -- Circuit Analysis under Process Variations -- FinFET Technology and design issues.

Sommario/riassunto

This book discusses the digital design of integrated circuits under process variations, with a focus on design-time solutions. The authors describe a step-by-step methodology, going from logic gates to logic paths to the circuit level. Topics are presented in comprehensively, without overwhelming use of analytical formulations. Emphasis is placed on providing digital designers with understanding of the sources of process variations, their impact on circuit performance and tools for improving their designs to comply with product specifications. Various circuit-level “design hints” are highlighted, so that readers can use them to improve their designs. A special treatment is devoted to unique design issues and the impact of process variations on the performance of FinFET based circuits. This book enables readers to make optimal decisions at design time, toward more efficient circuits, with better yield and higher reliability.
